HIOKI

DC HIPOT TESTER ST5680



Bring additional inspection performance to safety testing. Accelerate battery quality improvements with waveform analysis.

Product concept

Growing adoption of electric vehicles (EVs) and self-driving technology is leading to more rigorous reliability requirements for automotive components, pushing up quality.Degradation of EV batteries and related issues can lead to serious accidents, including fire.Consequently, safety and quality control are becoming even more important than in the past.

Market requirements

"Manufacturers want to manage test results using waveform data to verify battery quality." "Manufacturers want to conduct shipping inspections (DC withstand voltage tests) that comply with a range of international standards."

The ST5680 is a DC Hipot tester that was developed to meet these battery market requirements.







Preventing the shipment of batteries with latent defects that could lead to fires.



Waveform display function

Verify insulation performance with waveforms and values.

The ST5680 is a DC Hipot tester that can perform DC withstand voltage testing and insulation resistance testing in compliance with a variety of safety standards. In addition to generating PASS/FAIL judgments, the instrument can display and record applied voltage waveforms and leakage current waveforms acquired during testing. Its ability to visualize and analyze testing is useful from a test traceability standpoint.

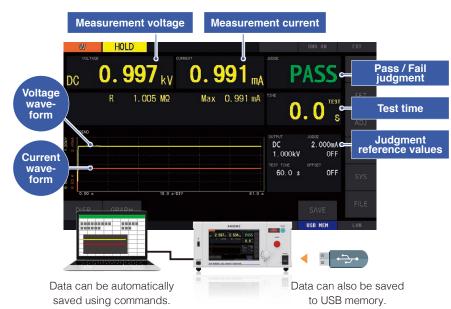
Waveform display of applied voltage and measured current

The behavior of the applied voltage and measured current can be checked by monitoring the waveforms. In addition, the instrument can display voltage, current, and resistance measured values as a time series so that behavior can be reviewed.

It can also display an enlarged view of just the waveforms for more detailed review. In this way, the ST5680 lets you analyze results immediately in the field, without using a computer.



Enlarged display of waveforms only



Advantages of the waveform display

Improving production processes

By analyzing waveforms during testing, you can infer the causes of defects in production processes

And by identifying those causes and improving the processes, you can improve production efficiency.



Improving production efficiency

Analyzing defective parts returned from the market

You can also look back at results, at the waveform level, from shipping inspections of products that were later returned due to defects. By improving the standards based on which PASS judgments are made, you can boost production quality



Improving production quality

Promoting inspection quality

The ability to record and manage waveforms is useful from an inspection traceability standpoint.

By developing higher-quality testing structures, you can increase the trust of customers



Improving reliability

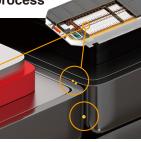
Prevent minuscule failures due to arc discharges.

The ST5680 can detect arc discharges, which are caused by residual materials like burrs and cuttings. By correctly identifying parts with minuscule insulation defects as defective, the instrument helps prevent the risk of hazards such as fires and accidents caused by heating after shipment.

Contamination with foreign material during the production process



Burrs at a weld location



Foreign material between cells

Detection of arc discharges triggering a FAIL judgment



The foreign material burns up, causing damage.

Contact check function

Preventing testing do-overs due to erroneous judgments

The instrument can determine whether it has made proper contact with the test target by measuring the capacitance between the measurement terminals (stray capacitance and the capacitance of the test target).



Functionality

The instrument offers convenient functionality that helps perform withstand voltage testing safely.

Voltage limitation function

Sets an upper limit for the voltage output by the instrument. This function helps prevent accidents due to erroneous settings. The setting range is 0.010 kV to 8.000 kV.

Auto range function

When the range is fixed, measured values outside the range are not displayed. When using the auto range function, the range is switched automatically according to measured values, allowing measured values to be displayed at all times.

Auto discharge function

Once each test is complete, the instrument switches automatically to an internal discharge circuit to discharge any residual charge held by the test target. This function helps prevent electric shock due to contact with a circuit in a charged state.

Panel memory function

This function stores test conditions in the instrument's memory for future recall as necessary. The memory can hold up to 64 sets conditions each for DC withstand voltage testing mode and insulation resistance testing mode.

Interlock function

This function disables instrument output based on the status of an external device or other hardware to ensure worker safety. It can be disabled using the included interlock cancellation jig, which is affixed to the EXT I/O port.

GFI function

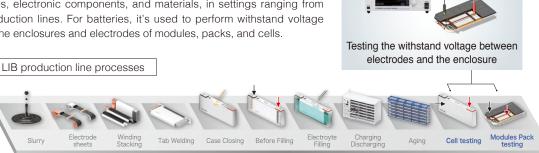
This function shuts down the output if a current of 0.5 mA or more flows from the high-voltage output section of the instrument to the ground section of the instrument during the withstand voltage test. It serves to reduce damage in the event of an electric shock caused by worker inattention.



Featuring testing quality that's a step above. Accommodate the full array of DC withstand voltage testing applications with specs that comply with a broad range of international standards.

Ideal for withstand voltage testing of batteries, motors, electronic components, and other parts

The ST5680 tests insulation performance by applying a high voltage to the test target. It's capable of performing safety testing for a broad assortment of targets, including electronic devices, electronic components, and materials, in settings ranging from R&D labs to production lines. For batteries, it's used to perform withstand voltage testing between the enclosures and electrodes of modules, packs, and cells.



1 Power supply performance that satisfies test conditions defined by international standards

Output voltage: Max. 8 kV Output current: Max. 100 mA

The ST5680 provides two modes: DC withstand voltage test mode, which evaluates insulation by measuring the leakage current in the test target, and insulation resistance test mode, which evaluates insulation by measuring resistance. In DC withstand voltage testing, it can output up to 8 kV, one of the highest values for any instrument of its kind. Test cycle times can be reduced since it can charge test targets quickly with high-capacity, 100 mA output, even if the target includes a capacitance component.

2 Stable high-voltage output

Perform tests without worrying about the capacitance component.

Even if your test target includes a capacitance component, an overshoot-resistant design ensures the ST5680 won't exceed the set voltage when applying voltage to the target, allowing you to perform tests with peace of mind. In addition, you can set a delay time so that no judgments are made while the charging current continues to flow, helping prevent erroneous judgments.

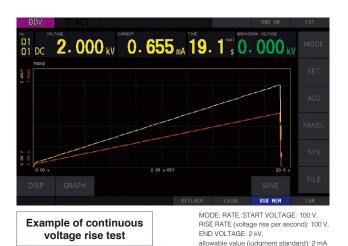
3 Precise testing of insulation by generating judgments based on minuscule current values

High-precision judgments with a maximum resolution of 0.001 μA

As the insulation performance of batteries and motors improves, there's growing demand for the ability to use ever more minuscule current values to generate PASS/FAIL judgments in withstand voltage testing. If you use a withstand voltage tester with low resolution, you won't be able to accurately measure leakage current. Since the ST5680 realizes high-precision performance with a maximum resolution of 0.001 μ A, it can accurately measure minuscule leakage currents and use them to generate PASS/FAIL judgments.

Insulation breakdown voltage (BDV) measurement function

The ST5680's BDV function can check the insulation breakdown voltage of the test target. It can increase the applied voltage at a set speed and check the voltage that leads to insulation breakdown. Test methods are defined by standards, including continuous voltage rise testing and stepped voltage rise testing. The ST5680 can perform both tests. The instrument can be used to evaluate insulation performance (dielectric strength) in R&D work.

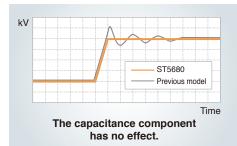




Example of stepped voltage rise testing

MODE: STEP, START VOLTAGE: 100 V, RISE RATE (voltage rise per second): 100 V, HOLD TIME: 1 s, number of steps: 20, allowable value (judgment standard): 2 mA







IEC 60243,

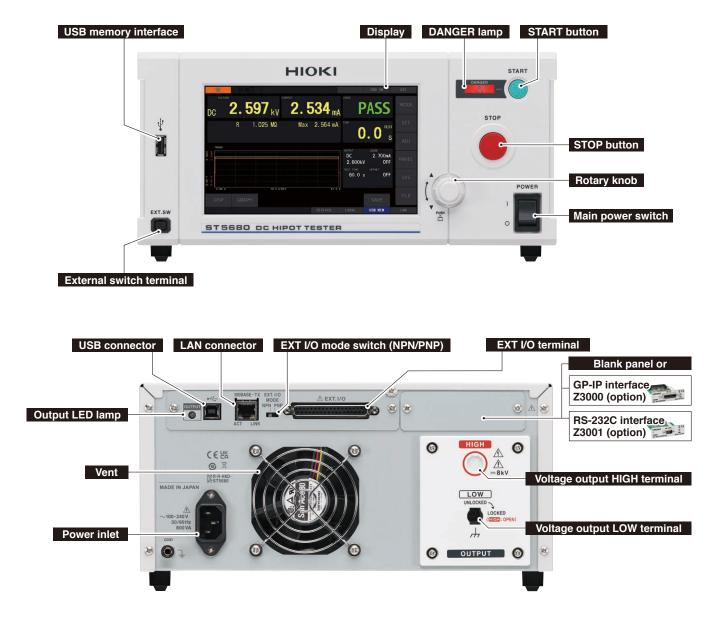
JIS C2110, etc.

Support for standard-

compliant testing

5

Interfaces



Options



HIGH VOLTAGE TEST LEAD L2260 Clip to special connector, red and black, 1.5 m



GP-IB CONNECTOR CABLE 9151-02 For the Z3000, 2 m



UNPROCESSED LEAD CABLE L2261 Bare wire to special connector, red and black, 5 m



RS-232C CABLE L9637 For the Z3001, 9-pin to 9-pin, cross, 3 m



GP-IB INTERFACE Z3000 For external control use



REMOTE CONTROL BOX (SINGLE) 9613 For starting/stopping measurement, one-handed use, 1.5 m



RS-232C INTERFACE Z3001 For external control use



REMOTE CONTROL BOX (DUAL) 9614 For starting/stopping measure-

ment, two-handed use, 1.5 m

External control and other communications interfaces

EXT I/O

LAN

USB GP-IB (option)

RS-232C (option)

The instrument ships standard with LAN and USB connectors. An optional GP-IB or RS-232C interface can also be added. The instrument can be connected to a PC or programmable logic controller (PCL), which can be used to control it and retrieve test results. Furthermore, the instrument provides external I/O terminals to facilitate instrument control and retrieval of instrument status and judgment results.

EXT I/O interface

The EXT I/O connector on the rear of the instrument can be used to control the instrument by outputting TEST signals and judgment result signals and inputting START and STOP signals.

Signal nameFunctionalityI/OSTARTTest start and W-IR/IR-W, program, and BDV mode trigger signalInINTERLOCKInterlock cancellationInLOAD1InInLOAD3Panel loadInLOAD5Panel loadInLOAD7Insulated power supply +5 V (-5 V) output-ISO_COMInsulated power supply common-ERRMeasurement error outputOutU_FAILOutput at UPPER_FAIL judgmentOutH.V.ONOutput during voltage generationOutW-FAILOutput at completion of each step during program testingOutSTEP_ENDOutput at arc detectionOutPASSOutput during testing (customer function)OutSTOPTest stop and PASS/FAIL hold cancellationInLOAD2Panel loadInLOAD4InInLOAD5Output at standby stateOutTESTOutput during testing (customer function)OutSTOPTest stop and PASS/FAIL hold cancellationInLOAD4InInLOAD5InInLOAD6InInREADYOutput at contact errorOutREADYOutput at contact errorOutREADYOutput at contact errorOutINSource etstingOutINInInIDAD2Output at contact errorOutIDAD4Output at contact errorOutIR-FAILOutput a	IN: Signal	input to instrument OUT: Signal output from ir	nstrument
STATU BDV mode trigger signal Interlock cancellation Interlock lnterlock cancellation In LOAD1 Interlock cancellation In In LOAD3 Panel load In LOAD5 Insulated power supply +5 V (-5 V) output - ISO_COM Insulated power supply common - ERR Measurement error output Out U_FAIL Output at UPPER_FAIL judgment Out L_FAIL Output at COWER_FAIL judgment Out W-FAIL Output at FAIL state during withstand voltage testing Out W-FAIL Output at FAIL state during withstand voltage testing Out W-MODE Output at completion of each step during program testing Out V-MODE Output at arc detection Out PASS Output at PASS judgment Out STOP Test stop and PASS/FAIL hold cancellation In LOAD0 In In In LOAD2 Panel load execution In In LOAD6 In In In LOA	Signal name	Functionality	I/O
LOAD1 LOAD3 LOAD5In In In In In ISO_5VInsulated power supply +5 V (-5 V) output In In ISO_COMInsulated power supply common ImISO_COMInsulated power supply common-ERRMeasurement error outputOut U U_FAILOutput at UPPER_FAIL judgmentOut U U VITAILH.V.ONOutput at LOWER_FAIL judgmentOut U VITAIR Could uring voltage generationOut UW-FAILOutput at LOWER_FAIL judgmentOut VITAIR Could uring withstand voltage testingOutW-MODEOutput at FAIL state during withstand voltage testingOutW-MODEOutput at completion of each step during program testingOutSTEP_ENDOutput at arc detectionOutPASSOutput at PASS judgmentOutTESTOutput during testing (customer function)OutSTOPTest stop and PASS/FAIL hold cancellationInLOAD0InInLOAD2Panel load executionInID_VALIDPanel load executionInIS_COMInsulated power supply common-READYOutput at standby stateOutREADYOutput at Completion of final step during program testingOutIR-FAILOutput at Completion of final step during program testingOutIR-FAILOutput at completion of final step during program testingOutID_VALIDOutput at completion of final step during program testingOutID_TOGeneral-purpose outputOut	START	Test start and W-IR/IR-W, program, and BDV mode trigger signal	In
LOAD3 LOAD5InLOAD5InLOAD7InISO_SVInsulated power supply +5 V (-5 V) outputISO_COMInsulated power supply commonERRMeasurement error outputOutput at UPPER_FAIL judgmentOutL_FAILOutput at LOWER_FAIL judgmentOutH.V.ONOutput at LOWER_FAIL judgmentOutW-FAILOutput at LOWER_FAIL judgmentOutW-FAILOutput at Completion of each step during program testingOutW-MODEOutput at completion of each step during program testingOutARC_DETOutput at ar cetectionOutPASSOutput during testing (customer function)OutSTEP_ENDTest stop and PASS/FAIL hold cancellationInLOAD0InInLOAD2Panel loadInILOAD4InInLOAD5InInLOAD6Output at standby stateOutPROTECTIONOutput at protection function operationOutREADYOutput at completion of final step duringOutIR-FAILOutput at completion of final step duringOutIR-FAILOutput at completion of final step duringOut	INTERLOCK	Interlock cancellation	In
LOAD5Panel loadInLOAD7Insulated power supply +5 V (-5 V) output-ISO_5VInsulated power supply common-ERRMeasurement error outputOutU_FAILOutput at UPPER_FAIL judgmentOutL_FAILOutput at UVPER_FAIL judgmentOutH.V.ONOutput at LOWER_FAIL judgmentOutW-FAILOutput at LOWER_FAIL judgmentOutW-FAILOutput during vithstand voltage testingOutW-FAILOutput at FAIL state during withstand voltage testingOutW-MODEOutput at completion of each step during program testingOutARC_DETOutput at arc detectionOutPASSOutput at PASS judgmentOutTESTOutput during testing (customer function)OutSTOPTest stop and PASS/FAIL hold cancellationInLOAD0InnInnLOAD4Panel loadInID_VALIDPanel load executionInISO_COMInsulated power supply common-READYOutput at standby stateOutPROTECTIONOutput at protection function operationOutIR-FAILOutput at Contact errorOutIR-FAILOutput at completion of final step during program testingOutIR-FAILOutput at completion of final step during program testingOutIR-FAILOutput at completion of final step during program testingOutIR-FAILOutput at completion of final step during program testing<	LOAD1		In
LOAD5InLOAD7Insulated power supply +5 V (-5 V) outputISO_5VInsulated power supply commonISO_COMInsulated power supply commonERRMeasurement error outputOutU_FAILOutput at UPPER_FAIL judgmentOutL_FAILOutput at LOWER_FAIL judgmentOutH.V.ONOutput during voltage generationOutW-FAILOutput during voltage generationOutW-MODEOutput during withstand voltage testingOutSTEP_ENDOutput at completion of each step during program testingOutARC_DETOutput at arc detectionOutPASSOutput during testing (customer function)OutSTOPTest stop and PASS/FAIL hold cancellationInLOAD0InInLOAD2Panel loadInILOAD4InInISO_COMInsulated power supply common-READYOutput at standby stateOutPROTECTIONOutput at protection function operationOutREADYOutput at contact errorOutIR-FAILOutput at Contact errorOutIR-FAILOutput at Completion of final step during program testingOutIR-FAILOutput at completion of final step during program testingOut	LOAD3	Papel load	In
ISO_5VInsulated power supply +5 V (-5 V) output-ISO_COMInsulated power supply common-ERRMeasurement error outputOutU_FAILOutput at UPPER_FAIL judgmentOutL_FAILOutput at LOWER_FAIL judgmentOutH.V.ONOutput during voltage generationOutW-FAILOutput at FAIL state during withstand voltage testingOutW-MODEOutput during withstand voltage testingOutW-MODEOutput at completion of each step during program testingOutARC_DETOutput at arc detectionOutPASSOutput during testing (customer function)OutSTOPTest stop and PASS/FAIL hold cancellationInEXT_ENInput signal enable for external I/O signalsInLOAD0Insulated power supply common-READYOutput at standby stateOutPROTECTIONOutput at protection function operationOutREADYOutput at contact errorOutIR-FAILOutput at Contact errorOutIR-FAILOutput at Contact errorOutIR-FAILOutput at contact errorOutIR-FAILOutput at Completion of final step during program testingOut	LOAD5	Faller IDau	In
ISO_COMInsulated power supply common-ERRMeasurement error outputOutU_FAILOutput at UPPER_FAIL judgmentOutL_FAILOutput at LOWER_FAIL judgmentOutH.V.ONOutput during voltage generationOutW-FAILOutput during voltage generationOutW-MODEOutput at FAIL state during withstand voltage testingOutW-MODEOutput during withstand voltage testingOutSTEP_ENDOutput at completion of each step during program testingOutARC_DETOutput at arc detectionOutPASSOutput at PASS judgmentOutSTOPTest stop and PASS/FAIL hold cancellationInEXT_ENInput signal enable for external I/O signalsInLOAD0InInLOAD6InInLD_VALIDPanel load executionInISO_COMInsulated power supply common-READYOutput at contact errorOutREADYOutput at FAIL state during insulation resistance testingOutIR-FAILOutput at contact errorOutIR-FAILOutput at completion of final step during program testingOutOUT0General-purpose outputOut	LOAD7		In
ERRMeasurement error outputOutU_FAILOutput at UPPER_FAIL judgmentOutL_FAILOutput at LOWER_FAIL judgmentOutH.V.ONOutput during voltage generationOutW-FAILOutput during voltage generationOutW-FAILOutput at FAIL state during withstand voltage testingOutW-MODEOutput during withstand voltage testingOutSTEP_ENDOutput at completion of each step during program testingOutARC_DETOutput at arc detectionOutPASSOutput during testing (customer function)OutSTOPTest stop and PASS/FAIL hold cancellationInEXT_ENInput signal enable for external I/O signalsInLOAD0InInLOAD6InInLD_VALIDPanel load executionInISO_COMInsulated power supply common-READYOutput at contact errorOutIR-FAILOutput at contact errorOutIR-FAILOutput at contact errorOutIR-FAILOutput at contact errorOutIR-FAILOutput during insulation resistance testingOutIR-MODEOutput at completion of final step during program testingOut	ISO_5V	Insulated power supply +5 V (-5 V) output	-
U_FAILOutput at UPPER_FAIL judgmentOutL_FAILOutput at LOWER_FAIL judgmentOutH.V.ONOutput during voltage generationOutW-FAILOutput at FAIL state during withstand voltage testingOutW-MODEOutput during withstand voltage testingOutSTEP_ENDOutput at completion of each step during program testingOutARC_DETOutput at arc detectionOutPASSOutput during testing (customer function)OutSTOPTest stop and PASS/FAIL hold cancellationInEXT_ENInput signal enable for external I/O signalsInLOAD0InInLOAD4Panel loadInID_VALIDPanel load executionInISO_COMInsulated power supply common-READYOutput at contact errorOutIR-FAILOutput at contact errorOutIR-FAILOutput at completion of final step during program testingOutOUT0General-purpose outputOut	ISO_COM	Insulated power supply common	-
L_FAILOutput at LOWER_FAIL judgmentOutH.V.ONOutput during voltage generationOutW-FAILOutput at FAIL state during withstand voltage testingOutW-MODEOutput during withstand voltage testingOutSTEP_ENDOutput at completion of each step during program testingOutARC_DETOutput at arc detectionOutPASSOutput at PASS judgmentOutTESTOutput during testing (customer function)OutSTOPTest stop and PASS/FAIL hold cancellationInEXT_ENInput signal enable for external I/O signalsInLOAD0InInLOAD4Panel loadInID_VALIDPanel load executionInISO_COMInsulated power supply common-READYOutput at contact errorOutREADYOutput at FAIL state during insulation resistance testingOutIR-FAILOutput at completion of final step during program testingOutOUT0General-purpose outputOut	ERR	Measurement error output	Out
H.V.ONOutput during voltage generationOutW-FAILOutput at FAIL state during withstand voltage testingOutW-MODEOutput during withstand voltage testingOutSTEP_ENDOutput at completion of each step during program testingOutARC_DETOutput at ac detectionOutPASSOutput at PASS judgmentOutTESTOutput during testing (customer function)OutSTOPTest stop and PASS/FAIL hold cancellationInEXT_ENInput signal enable for external I/O signalsInLOAD0InInLOAD2Panel loadInLOAD6InInLD_VALIDPanel load executionInISO_COMInsulated power supply common-READYOutput at rontection function operationOutReferenceOutput at contact errorOutIR-FAILOutput at contact errorOutIR-FAILOutput at completion of final step during program testingOutOUT0General-purpose outputOut	U_FAIL	Output at UPPER_FAIL judgment	Out
W-FAILOutput at FAIL state during withstand voltage testingOutW-MODEOutput during withstand voltage testingOutSTEP_ENDOutput at completion of each step during program testingOutARC_DETOutput at arc detectionOutPASSOutput at PASS judgmentOutTESTOutput during testing (customer function)OutSTOPTest stop and PASS/FAIL hold cancellationInEXT_ENInput signal enable for external I/O signalsInLOAD0InInLOAD2Panel loadInLOAD6InInLD_VALIDPanel load executionInISO_COMInsulated power supply common-READYOutput at contact errorOutOutput at FAIL state during insulation resistance testingOutIR-FAILOutput at completion of final step during program testingOutOUT0General-purpose outputOut	L_FAIL	Output at LOWER_FAIL judgment	Out
W-FAIL voltage testing Out W-MODE Output during withstand voltage testing Out STEP_END Output at completion of each step during program testing Out ARC_DET Output at arc detection Out PASS Output at PASS judgment Out TEST Output during testing (customer function) Out STOP Test stop and PASS/FAIL hold cancellation In LOAD0 Input signal enable for external I/O signals In LOAD2 Panel load In LOAD6 In In LOAD6 In In LD_VALID Panel load execution In ISO_COM Insulated power supply common - READY Output at standby state Out PROTECTION Output at contact error Out IR-FAIL Output at FAIL state during insulation resistance testing Out IR-MODE Output at completion of final step during Out PROG_END Output at completion of final step during Out	H.V.ON	Output during voltage generation	Out
STEP_ENDOutput at completion of each step during program testingOutARC_DETOutput at arc detectionOutPASSOutput at PASS judgmentOutTESTOutput during testing (customer function)OutSTOPTest stop and PASS/FAIL hold cancellationInEXT_ENInput signal enable for external I/O signalsInLOAD0InInLOAD2Panel loadInLOAD6InInLD_VALIDPanel load executionInISO_COMInsulated power supply common-READYOutput at contact errorOutCONT_ERROutput at contact errorOutIR-FAILOutput at completion of final step during program testingOutOUT0General-purpose outputOutOUT0General-purpose outputOut	W-FAIL		Out
STEP_ENDprogram testingTotalARC_DETOutput at arc detectionOutPASSOutput at PASS judgmentOutTESTOutput during testing (customer function)OutSTOPTest stop and PASS/FAIL hold cancellationInEXT_ENInput signal enable for external I/O signalsInLOAD0InInLOAD2Panel loadInLOAD6InInLD_VALIDPanel load executionInISO_COMInsulated power supply common-READYOutput at standby stateOutPOTECTIONOutput at contact errorOutIR-FAILOutput at FAIL state during insulation resistance testingOutIR-MODEOutput at completion of final step during program testingOutOUT0General-purpose outputOut	W-MODE	Output during withstand voltage testing	Out
PASS Output at PASS judgment Out TEST Output during testing (customer function) Out STOP Test stop and PASS/FAIL hold cancellation In EXT_EN Input signal enable for external I/O signals In LOAD0 In In LOAD2 Panel load In LOAD6 In In LOAD6 In In LOAD6 In In LOAD6 In In LOAD6 Output at standby state Out READY Output at protection function operation Out RFFAIL Output at contact error Out IR-FAIL Output at FAIL state during insulation resistance testing Out IR-MODE Output at completion of final step during Out PROG_END Output at completion of final step during Out	STEP_END		Out
TEST Output during testing (customer function) Out STOP Test stop and PASS/FAIL hold cancellation In EXT_EN Input signal enable for external I/O signals In LOAD0 In In LOAD2 Panel load In LOAD4 Panel load execution In LOAD6 In In LOAD6 In In LOAD6 In In LOAD6 Output at standby state Out PROTECTION Output at protection function operation Out R-FAIL Output at FAIL state during insulation resistance testing Out IR-FAIL Output at completion of final step during Out PROG_END Output at completion of final step during Out OUT0 General-purpose output Out Out	ARC_DET	Output at arc detection	Out
STOP Test stop and PASS/FAIL hold cancellation In EXT_EN Input signal enable for external I/O signals In LOAD0 In In LOAD2 Panel load In LOAD6 In In RSO_COM Insulated power supply common - READY Output at standby state Out PROTECTION Output at protection function operation Out CONT_ERR Output at contact error Out IR-FAIL Output at FAIL state during insulation resistance testing Out IR-MODE Output during insulation resistance testing Out PROG_END Output at completion of final step during program testing Out OUT0 General-purpose output Out Out	PASS	Output at PASS judgment	Out
EXT_EN Input signal enable for external I/O signals In LOAD0 In In LOAD2 Panel load In LOAD4 Panel load execution In LOAD6 In In LOAD6 In In LOAD6 In In LOAD6 In In LD_VALID Panel load execution In ISO_COM Insulated power supply common - READY Output at standby state Out PROTECTION Output at protection function operation Out CONT_ERR Output at contact error Out IR-FAIL Output at FAIL state during insulation resistance testing Out IR-MODE Output at completion of final step during program testing Out OUT0 General-purpose output Out Out	TEST	Output during testing (customer function)	Out
LOAD0 In LOAD2 Panel load In LOAD4 In In LOAD6 In In LD_VALID Panel load execution In ISO_COM Insulated power supply common - READY Output at standby state Out PROTECTION Output at protection function operation Out CONT_ERR Output at contact error Out IR-FAIL Output at FAIL state during insulation resistance testing Out IR-MODE Output at completion of final step during program testing Out OUT0 General-purpose output Out	STOP	Test stop and PASS/FAIL hold cancellation	In
LOAD2 In LOAD4 In LOAD6 In LOAD6 In LD_VALID Panel load execution In ISO_COM Insulated power supply common - READY Output at standby state Out PROTECTION Output at protection function operation Out CONT_ERR Output at FAIL state during insulation resistance testing Out IR-FAIL Output during insulation resistance testing Out PROG_END Output at completion of final step during program testing Out OUT0 General-purpose output Out	EXT_EN	Input signal enable for external I/O signals	In
LOAD4 Panel load In LOAD6 In In LD_VALID Panel load execution In ISO_COM Insulated power supply common - READY Output at standby state Out PROTECTION Output at protection function operation Out CONT_ERR Output at FAIL state during insulation resistance testing Out IR-FAIL Output during insulation resistance testing Out IR-MODE Output at completion of final step during program testing Out OUT0 General-purpose output Out	LOAD0		In
LOAD4 In LOAD6 In LD_VALID Panel load execution In ISO_COM Insulated power supply common - READY Output at standby state Out PROTECTION Output at protection function operation Out CONT_ERR Output at contact error Out IR-FAIL Output at FAIL state during insulation resistance testing Out IR-MODE Output at completion of final step during program testing Out OUT0 General-purpose output Out	LOAD2	Department	In
LD_VALIDPanel load executionInISO_COMInsulated power supply common-READYOutput at standby stateOutPROTECTIONOutput at protection function operationOutCONT_ERROutput at contact errorOutIR-FAILOutput at FAIL state during insulation resistance testingOutIR-MODEOutput during insulation resistance testingOutOUTOGeneral-purpose outputOut	LOAD4	Panerioad	In
ISO_COM Insulated power supply common - READY Output at standby state Out PROTECTION Output at protection function operation Out CONT_ERR Output at contact error Out IR-FAIL Output at FAIL state during insulation resistance testing Out IR-MODE Output at completion of final step during program testing Out OUT0 General-purpose output Out	LOAD6		In
READY Output at standby state Out PROTECTION Output at protection function operation Out CONT_ERR Output at contact error Out IR-FAIL Output at FAIL state during insulation resistance testing Out IR-MODE Output at completion of final step during program testing Out OUTO General-purpose output Out	LD_VALID	Panel load execution	In
PROTECTION Output at protection function operation Out CONT_ERR Output at contact error Out IR-FAIL Output at FAIL state during insulation resistance testing Out IR-MODE Output at completion of final step during program testing Out OUTO General-purpose output Out	ISO_COM	Insulated power supply common	-
CONT_ERR Output at contact error Out IR-FAIL Output at FAIL state during insulation resistance testing Out IR-MODE Output during insulation resistance testing Out PROG_END Output at completion of final step during program testing Out OUTO General-purpose output Out	READY	Output at standby state	Out
IR-FAIL Output at FAIL state during insulation resistance testing Out IR-MODE Output during insulation resistance testing Out PROG_END Output at completion of final step during program testing Out OUTO General-purpose output Out	PROTECTION	Output at protection function operation	Out
IR-FAIL resistance testing Out IR-MODE Output during insulation resistance testing Out PROG_END Output at completion of final step during program testing Out OUT0 General-purpose output Out	CONT_ERR	Output at contact error	Out
PROG_END Output at completion of final step during program testing Out OUT0 General-purpose output Out	IR-FAIL		Out
OUTO General-purpose output Out	IR-MODE	Output during insulation resistance testing	Out
- · · · ·	PROG_END		Out
OUT1 General-purpose output Out	OUT0	General-purpose output	Out
	OUT1	General-purpose output	Out

About interlock functionality

Interlock functionality serves to shut off instrument output. When the interlock function operates, START key operation is disabled. Similarly, test operation cannot be started using the EXT I/O START signal or communications commands.

To start testing, use the included interlock cancellation jig to turn off the interlock function.

LAN interface

The instrument provides an Ethernet 100Base-TX interface. A 10Base-T or 100Base-TX compatible LAN cable can be used to connect the instrument to a network so that it can be controlled by a PC or other device.

EXT I/O mode switch (NPN/PNP)

The EXT I/O mode switch (NPN/PNP), which switches between current sink (NPN) and current source (NPN) operation, can be used to change the type of programmable logic controller (PLC) that the instrument supports.

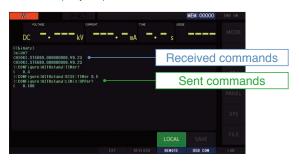
I/O handler test function

This function lets you check whether output signals are being properly output from the EXT I/O terminal and whether input signals are being properly read.

< SYS							1/0	
I/O OUT								
U_FAIL	1	AIL	H.V.ON	W-FAIL	W-M	IODE	STEP_END	
ARC_DET	PA	SS	TEST	OUT2	REA	ADY	PROTECTION	
CONT_ERF	R I-F	AIL	I-MODE	PROG_EN	D OL	JTO	OUT1	
1/0 IN								
START	2	INTERLOCK	LOAD1	LOAD3	LOAD5	LOAD	7 10	
STOP	EXT_EN	LOADO	LOAD2	LOAD4	LOAD6	LD_VAL	ID 30	
EXT.I/O MODE	: NPN							

Command monitor function

This function, which displays commands and responses on the measurement screen, is a useful tool when creating programs. It can be used to display communications commands and query responses on the screen.



Color LCD display with touch screen

The instrument has a 7-inch color LCD display with a touch screen, improving visibility and making possible intuitive operation.



Specifications (Accuracy guaranteed for 1 year)

Output voltageDC 0.010 kV to 8.000 kV (1 V resolution)Load regulation $\pm 1\%$ or lessOutput setting accuracy $\pm (1.2\%$ of setting ± 20 V)Output current/cutoff currentMax. 100 mACurrent accuracy ≥ 3.00 mA: $\pm (1.5\%$ rdg. $\pm 2 \mu$ A) ≤ 3.00 mA: $\pm 1.5\%$ rdg.AMaximum resolution0.001 μ ATest time0.1 s to 999 s, continuous (timer off)Voltage ramp up / ramp down time0.1 s to 300 s / 0.1 s to 300 s, offShort-circuit current200 mA or lessTest modesW to IR, IR to W, program testInsulation resistance testOutput voltageOutput voltageDC 10 V to 2000 V (1 V resolution)Output setting accuracy $\pm (1.2\%$ of setting ± 2 V)Resistance value display range10.00 kΩ to 200.0 GΩ (0.01 kΩ resolution)Accuracy guarantee range10.00 kΩ to 200.0 GΩ (0.01 kΩ resolution)Voltage rise / fall time0.1 s to 300 s / 0.1 s to 300 s, offBreakdown voltage testInsulation breakdown voltage rise test, stepped voltage rise testSettingStart voltage, current, insulation resistanceSampling rate500 kS/sResolution256 K wordsArc discharge detection Detection methodCapacitance measurement methodSetting descriptionTest voltage variability: 1% to 50%Contact check functionalitySave to USB memorySetting descriptionTheshold (capacitance) setting: 1.0 nF to 100.0 nF	Main functions			
Breakdown voltage test Waveform display functionality Arc discharge detection Contact check function DC Hipot test Output voltage DC 0.010 kV to 8.000 kV (1 V resolution) Load regulation $\pm 1\%$ or less Output voltage DC 0.010 kV to 8.000 kV (1 V resolution) Load regulation $\pm 1\%$ or less Output current/cutoff current Max. 100 mA 2.00 mA: $\pm 1.5\%$ rdg. ± 3.00 mA: $\pm 1.5\%$ rdg. Maximum resolution 0.001 µA Test time 0.1 s to 300 s / 0.1 s to 300 s, off Voltage ramp up / ramp 0.1 s to 300 s / 0.1 s to 300 s, off Short-circuit current 200 mA or less Test modes W to IR, IR to W, program test Insulation resistance test Output voltage Output voltage DC 10 V to 2000 V (1 V resolution) Output setting accuracy $\pm (1.5\%$ rdg. + 3 dgt.) *See below for details Test time 0.1 s to 300 s / 0.1 s to 300 s, off Song rise Y Voltage rise / fall time 0.1 s to 300 s / 0.1 s to 300 s, off Test method Continuous voltage rise test, stepped voltage rise test Setting descr	DC Hipot test			
Waveform display functionality Arc discharge detection Contact check function DC Hipot test Output voltage DC 0.010 kV to 8.000 kV (1 V resolution) Load regulation ±1% or less Output setting accuracy $\pm (1.2\% \text{ of setting } + 20 \text{ V})$ Output current/cutoff current Max. 100 mA Current accuracy $\geq 3.00 \text{ mA}: \pm (1.5\% \text{ rdg}. + 2 \mu \text{A})$ Maximum resolution $0.001 \mu \text{A}$ Test time $0.1 \text{ s to 399 s, continuous (timer off)}$ Voltage ramp up / ramp down time $0.1 \text{ s to 300 s / 0.1 s to 300 s, off}$ Short-circuit current 200 mA or less Test modes W to IR, IR to W, program test Insulation resistance test Output voltage Output voltage accuracy $\pm (1.2\% \text{ of setting } + 2 \text{ V})$ Resistance accuracy $\pm (1.5\% \text{ rdg}. + 3 \text{ dg}.) "See below for details Test mede 0.1 \text{ s to 300 s / 0.1 s to 300 s, off Breakdown voltage test To 0.00 kΩ to 20.00 GΩ (0.01 kΩ resolution) Accuracy guarantee range 0.00 \text{ kQ} to 300 s / 0.1 s to 300 s, off Start voltage, end voltage, rise speed, arc detection, electrode distance, upper limit current Waveform disp$	Insulation resistance tes	t		
Arc discharge detectionContact check functionDC Hipot testOutput voltageDC 0.010 kV to 8.000 kV (1 V resolution)Load regulation $\pm 1\%$ or lessOutput setting accuracy $\pm 1.2\%$ of setting ± 20 V)Output current/cutoff currentMax. 100 mACurrent accuracy $\ge 3.00 \text{ mA}: \pm (1.5\% \text{ rdg}. \pm 2 \mu\text{A})$ Maximum resolution0.001 μA Test time0.1 s to 999 s, continuous (timer off)Voltage ramp up / ramp down time0.1 s to 300 s / 0.1 s to 300 s, offShort-circuit current200 mA or lessTest modesW to IR, IR to W, program testInsulation resistance test0.000 μ (1 V resolution)Output setting accuracy $\pm (1.2\% \text{ of setting } + 2 V)$ Resistance value display range10.00 kΩ to 200.0 GΩ (0.01 kΩ resolution)Accuracy guarante range test time0.1 s to 300 s / 0.1 s to 300 s, offOthage rise / fall time0.1 s to 300 s / 0.1 s to 300 s, offOutput setting accuracy display range $\pm 1.5\% \text{ rdg}. \pm 3 \text{ dg}.$) "See below for detailsTest time0.1 s to 300 s / 0.1 s to 300 s, offStart voltage testStart voltage, end voltage, rise speed, arc detection, electrode distance, upper limit currentWaveform display contentVoltage, current, insulation resistanceSampling rate500 kS/sResolution256 K wordsArc discharge detectionTest voltage variability: 1% to 50%Contract check functionalityCapacitance measurement methodSetting descriptionTest voltage varia	Breakdown voltage test			
Contact check function DC Hipot test Output voltage DC 0.010 kV to 8.000 kV (1 V resolution) Load regulation $\pm 1\%$ or less Output setting accuracy $\pm (1.2\%$ of setting ± 20 V) Output current/cutoff current Max. 100 mA Current accuracy ≥ 3.00 mA: $\pm 1.5\%$ rdg. $\pm 2 \mu$ A) ≤ 3.00 mA: $\pm 1.5\%$ rdg. Maximum resolution Maximum resolution 0.001 μ A Test time 0.1 s to 999 s, continuous (timer off) Voltage ramp up / ramp down time 0.1 s to 300 s / 0.1 s to 300 s, off Short-circuit current 200 mA or less Test modes W to IR, IR to W, program test Insulation resistance test Output voltage Output voltage DC 10 V to 2000 V (1 V resolution) Output voltage DC 10 V to 2000 G\Omega (0.01 k\Omega resolution) Accuracy guarantee range 10.00 k\Omega to 290.99 G\Omega Resistance accuracy $\pm (1.5\%$ rdg. + 3 dgt.) *See below for details Test time 0.1 s to 300 s / 0.1 s to 300 s, off Breakdown voltage test Insulation breakdown voltage (kV), insulation breakdown strength (kV/mm) Setting description Star voltage, end voltage, rise speed, arc detection, electrode distance, u	Waveform display functi	onality		
DC Hipot testOutput voltageDC 0.010 kV to 8.000 kV (1 V resolution)Load regulation \pm 1% or lessOutput setting accuracy \pm (1.2% of setting + 20 V)Output setting accuracy \pm 3.00 mA: \pm (1.5% rdg. + 2 µA) \leq 3.00 mA: \pm 1.5% rdg.Maximum resolution0.001 µATest time0.1 s to 999 s, continuous (timer off)Voltage ramp up / ramp down time0.1 s to 300 s / 0.1 s to 300 s, offShort-circuit current200 mA or lessTest modesW to IR, IR to W, program testInsulation resistance test0.001 μAOutput voltageDC 10 V to 2000 V (1 V resolution)Output voltageDC 10 V to 2000 Q (0.01 kΩ resolution)Accuracy guarantee range10.00 kΩ to 200.0 GΩ (0.01 kΩ resolution)Accuracy guarantee range10.00 kΩ to 99.99 GΩResistance accuracy \pm (1.5% rdg. + 3 dgt.) *See below for detailsTest time0.1 s to 300 s / 0.1 s to 300 s, offBreakdown voltage testInsulation breakdown voltage rise test, stepped voltage rise testSettingStart voltage, end voltage, rise speed, arc detection, electrode distance, upper limit currentWaveform display functionalityStart voltage, current, insulation resistanceSampling rate500 kS/sResolution256 K wordsArc discharge detectionTest voltage variability: 1% to 50%Contact check functionalityDetection methodMaveform display contentCapacitance measurement methodSetting descriptionTest voltage variability: 1.0 nF to 100.0 nF <th>Arc discharge detection</th> <th></th>	Arc discharge detection			
Output voltageDC 0.010 kV to 8.000 kV (1 V resolution)Load regulation $\pm 1\%$ or lessOutput setting accuracy $\pm (1.2\%$ of setting ± 20 V)Output current/cutoff currentMax. 100 mACurrent accuracy ≥ 3.00 mA: $\pm (1.5\%$ rdg. $\pm 2 \mu$ A) ≤ 3.00 mA: $\pm 1.5\%$ rdg. $\pm AA$ Maximum resolution0.001 μ ATest time0.1 s to 999 s, continuous (timer off)Voltage ramp up / ramp down time0.1 s to 300 s / 0.1 s to 300 s, offShort-circuit current200 mA or lessTest modesW to IR, IR to W, program testInsulation resistance test0.001 μ AOutput voltageDC 10 V to 2000 V (1 V resolution)Output setting accuracy $\pm (1.2\%$ of setting ± 2 V)Resistance value display range10.00 kΩ to 200.0 GΩ (0.01 kΩ resolution)Accuracy guarantee range10.00 kΩ to 99.99 GΩResistance accuracy $\pm (1.5\%$ rdg. ± 3 dgt.) "See below for detailsTest time0.1 s to 300 s / 0.1 s to 300 s, offVoltage rise / fall time0.1 s to 300 s / 0.1 s to 300 s, offSettingsInsulation breakdown voltage rise test, stepped voltage rise testSetting descriptionStart voltage, current, insulation breakdown strength (kV/mm)Setting description256 K wordsArc discharge detection nelectrode distance, upper limit currentWaveform display contentVoltage, current, insulation resistanceSampling rate500 kS/sResolution256 K wordsArc discharge detectionCapacitance measurement method <td>Contact check function</td> <td></td>	Contact check function			
Load regulation $\pm 1\%$ or lessOutput setting accuracy $\pm (1.2\% \text{ of setting } + 20 \text{ V})$ Output current/cutoff currentMax. 100 mACurrent accuracy $\geq 3.00 \text{ mA}$: $\pm (1.5\% \text{ rdg.} + 2 \mu \text{ A})$ $\leq 3.00 \text{ mA}$: $\pm (1.5\% \text{ rdg.} + 2 \mu \text{ A})$ Current accuracy $\geq 3.00 \text{ mA}$: $\pm (1.5\% \text{ rdg.} + 2 \mu \text{ A})$ Test time $0.01 \mu \text{ A}$ Test time $0.1 \text{ s to } 309 \text{ s, continuous (timer off)}$ Voltage ramp up / ramp down time $0.1 \text{ s to } 300 \text{ s / } 0.1 \text{ s to } 300 \text{ s, off}$ Short-circuit current200 mA or lessTest modesW to IR, IR to W, program testInsulation resistance testOutput voltageOutput voltageDC 10 V to 2000 V (1 V resolution)Output setting accuracy $\pm (1.2\% \text{ of setting } + 2 \text{ V})$ Resistance value display range $10.00 \ k\Omega to 200.0 \ G\Omega (0.01 \ k\Omega resolution)$ Accuracy guarantee range $10.00 \ k\Omega to 99.9 \ G\Omega$ Resistance accuracy $\pm (1.5\% \ rdg. + 3 \ dg.)^*$ See below for detailsTest time $0.1 \text{ s to } 300 \ s / 0.1 \text{ s to } 300 \ s, off$ Breakdown voltage testInsulation breakdown voltage rise test, stepped voltage rise testSettingsInsulation breakdown voltage (kV), insulation breakdown strength (kV/mm)Setting descriptionStart voltage, current, insulation resistanceSampling rate $500 \ kS/s$ Resolution256 K wordsArc discharge detection Detection methodCapacitance measurement methodSetting descriptionTest voltage variability: 1% to 50% <	DC Hipot test			
Output setting accuracy $\pm (1.2\% \text{ of setting } + 20 \text{ V})$ Output current/cutoff currentMax. 100 mACurrent accuracy $\geq 3.00 \text{ mA}$: $\pm (1.5\% \text{ rdg.} + 2 \mu \text{A})$ Solo mA: $\pm (1.5\% \text{ rdg.} + 2 \mu \text{A})$ $\leq 3.00 \text{ mA}$: $\pm (1.5\% \text{ rdg.} + 2 \mu \text{A})$ Maximum resolution0.001 μ ATest time0.1 s to 999 s, continuous (timer off)Voltage ramp up / ramp0.1 s to 300 s / 0.1 s to 300 s, offShort-circuit current200 mA or lessTest modesW to IR, IR to W, program testInsulation resistance test0.00 kΩ to 200.0 GΩ (0.01 kΩ resolution)Output voltageDC 10 V to 2000 V (1 V resolution)Output setting accuracy $\pm (1.2\% \text{ of setting } + 2 \text{ V})$ Resistance value10.00 kΩ to 200.0 GΩ (0.01 kΩ resolution)Accuracy guarantee range10.00 kΩ to 99.99 GΩResistance accuracy $\pm (1.5\% \text{ rdg.} + 3 \text{ dg.})$ "See below for detailsTest time0.1 s to 300 s / 0.1 s to 300 s, offBreakdown voltage testContinuous voltage rise test, stepped voltage rise testSettingsInsulation breakdown voltage (kV), insulation breakdown strength (kV/mm)Setting descriptionStart voltage, current, insulation resistanceSampling rate500 kS/sResolution256 K wordsArc discharge detectionTest voltage variability: 1% to 50%Contact check functionalityDetection methodDetection methodCapacitance measurement methodSetting descriptionTheshold (capacitance) setting: 1.0 nF to 100.0 nFMemory functionality<	Output voltage	DC 0.010 kV to 8.000 kV (1 V resolution)		
Output current/cutoff currentMax. 100 mACurrent accuracy \geq 3.00 mA: ±(1.5% rdg. + 2 µA) \leq 3.00 mA: ±1.5% rdg.Maximum resolution0.001 µATest time0.1 s to 999 s, continuous (timer off)Voltage ramp up / ramp down time0.1 s to 300 s / 0.1 s to 300 s, offShort-circuit current200 mA or lessTest modesW to IR, IR to W, program testInsulation resistance testOutput voltageOutput voltageDC 10 V to 2000 V (1 V resolution)Output setting accuracy±(1.2% of setting + 2 V)Resistance value display range10.00 kΩ to 200.0 GΩ (0.01 kΩ resolution)Accuracy guarantee range10.00 kΩ to 200.0 GΩ (0.01 kΩ resolution)Voltage rise / fall time0.1 s to 300 s / 0.1 s to 300 s, offBreakdown voltage test0.1 s to 300 s / 0.1 s to 300 s, offSettingsInsulation breakdown voltage rise test, stepped voltage rise testSettingsStart voltage, end voltage, rise speed, arc detection, electrode distance, upper limit currentWaveform display contentVoltage, current, insulation resistanceSampling rate500 kS/sResolution256 K wordsArc discharge detectionTest voltage variability: 1% to 50%Contact check functionalityDetection methodContact check functionalityDetection methodSetting descriptionTest voltage measurement methodSetting descriptionTest voltage measurement methodSetting descriptionTest voltage variability: 1% to 50%Contact check functionality <td>Load regulation</td> <td>±1% or less</td>	Load regulation	±1% or less		
Current accuracy $> 3.00 \text{ mA: } \pm (1.5\% \text{ rdg. } + 2 \mu \text{A})$ $\leq 3.00 \text{ mA: } \pm 1.5\% \text{ rdg.}$ Maximum resolution0.001 μA Test time0.1 s to 999 s, continuous (timer off)Voltage ramp up / ramp down time0.1 s to 300 s / 0.1 s to 300 s, offShort-circuit current200 mA or lessTest modesW to IR, IR to W, program testInsulation resistance testOutput voltageDC 10 V to 2000 V (1 V resolution)Output voltageDC 10 V to 200.0 G Ω (0.01 k Ω resolution)Accuracy guarantee range10.00 k Ω to 200.0 G Ω (0.01 k Ω resolution)Accuracy guarantee range10.00 k Ω to 99.99 G Ω Resistance accuracy $\pm (1.5\% \text{ rdg. + 3 dgt.})$ *See below for detailsTest time0.1 s to 300 s / 0.1 s to 300 s, offBreakdown voltage testInsulation breakdown voltage rise test, stepped voltage rise testSettingsInsulation breakdown voltage, rise speed, arc detection, electrode distance, upper limit currentWaveform display contentVoltage, current, insulation resistanceSampling rate500 kS/sResolution256 K wordsArc discharge detectionTest voltage variability: 1% to 50%Contact check functionalityTest voltage reasurement methodSetting descriptionTest voltage reasurement methodSetting descriptionTest voltage variability: 1% to 50%Contact check functionalitySave to USB memory	Output setting accuracy	±(1.2% of setting + 20 V)		
Current accuracy \leq 3.00 mA: ±1.5% rdg. Maximum resolution 0.001 μA Test time 0.1 s to 999 s, continuous (timer off) Voltage ramp up / ramp down time 0.1 s to 300 s / 0.1 s to 300 s, off Short-circuit current 200 mA or less Test modes W to IR, IR to W, program test Insulation resistance test 0.10 V to 2000 V (1 V resolution) Output voltage DC 10 V to 2000 GΩ (0.01 kΩ resolution) Output voltage 10.00 kΩ to 200.0 GΩ (0.01 kΩ resolution) Accuracy guarantee range 10.00 kΩ to 99.99 GΩ Resistance accuracy ±(1.5% rdg. + 3 dgt.) *See below for details Test time 0.1 s to 300 s / 0.1 s to 300 s, off Breakdown voltage test Test method Continuous voltage rise test, stepped voltage rise test Insulation breakdown voltage (kV), insulation breakdown strength (kV/mm) Setting Start voltage, end voltage, rise speed, arc detection, electrode distance, upper limit current Waveform display functionality Waveform display content Waveform display content Voltage, current, insulation resistance Sampling rate 500 kS/s Resolution 256 K words Arc discharge detection Detection m	Output current/cutoff current	Max. 100 mA		
SourceSourceMaximum resolution0.001 μ ATest time0.1 s to 999 s, continuous (timer off)Voltage ramp up / ramp down time0.1 s to 300 s / 0.1 s to 300 s, offShort-circuit current200 mA or lessTest modesW to IR, IR to W, program testInsulation resistance testInsulation resistance testOutput voltageDC 10 V to 2000 V (1 V resolution)Output voltageDC 10 V to 2000 G (0.01 k 0 resolution)Accuracy guarantee range10.00 k 0 to 99.99 G 0Resistance accuracy $\pm (1.5\% rdg. + 3 dgt.)$ "See below for detailsTest time0.1 s to 999 s, continuous (timer off)Voltage rise / fall time0.1 s to 300 s / 0.1 s to 300 s, offBreakdown voltage testInsulation breakdown voltage rise test, stepped voltage rise testSettingInsulation breakdown voltage, rise speed, arc detection, electrode distance, upper limit currentWaveform display contentVoltage, current, insulation resistanceSampling rate500 kS/sResolution256 K wordsArc discharge detectionTest voltage variability: 1% to 50%Detection methodMonitoring of fluctuations in the test voltageSetting descriptionTest voltage variability: 1.0 nF to 100.0 nFMemory functionalitySave to USB memory	Current accuracy			
Test time 0.1 s to 999 s, continuous (timer off) Voltage ramp up / ramp down time 0.1 s to 300 s / 0.1 s to 300 s, off Short-circuit current 200 mA or less Test modes W to IR, IR to W, program test Insulation resistance test 0.00 kΩ to 2000 V (1 V resolution) Output voltage DC 10 V to 2000 V (1 V resolution) Output setting accuracy ±(1.2% of setting + 2 V) Resistance value 10.00 kΩ to 200.0 GΩ (0.01 kΩ resolution) display range 10.00 kΩ to 99.99 GΩ Resistance accuracy ±(1.5% rdg. + 3 dgt.) *See below for details Test time 0.1 s to 300 s / 0.1 s to 300 s, off Breakdown voltage test 0.1 s to 300 s / 0.1 s to 300 s, off Breakdown voltage test Insulation breakdown voltage (kV), insulation breakdown strength (kV/mm) Setting Insulation breakdown voltage, rise speed, arc detection, electrode distance, upper limit current Waveform display functionality Waveform display functionality Waveform display content Voltage, current, insulation resistance Sampling rate 500 kS/s Resolution 256 K words Arc discharge detection Test voltage variability: 1% to 50% Contact check functional		≤ 3.00 mA: ±1.5% rdg.		
Voltage ramp up / ramp down time $0.1 ext{s}$ to $300 ext{s}$ / $0.1 ext{s}$ to $300 ext{s}$, offShort-circuit current $200 ext{ mA}$ or lessTest modesW to IR, IR to W, program testInsulation resistance testOutput voltageOutput voltageDC 10 V to $2000 ext{V}$ (1 V resolution)Output setting accuracy $\pm (1.2\% ext{ of setting } + 2 ext{V})$ Resistance value display range $10.00 ext{ kD} ext{ to } 200.0 ext{ GO} (0.01 ext{ kD} resolution)$ Accuracy guarantee range $10.00 ext{ kD} ext{ to } 29.99 ext{ GO}$ Resistance accuracy $\pm (1.5\% ext{ rdg. + 3 ext{ dgt.})$ *See below for detailsTest time $0.1 ext{ s} ext{ og99 ext{ s}, continuous (timer off)$ Voltage rise / fall time $0.1 ext{ s} ext{ o300 ext{ s}} / 0.1 ext{ s} ext{ o300 ext{ s}}, offBreakdown voltage testTest methodContinuous voltage rise test, stepped voltage rise testSettingsInsulation breakdown voltage (kV), insulation breakdownstrength (kV/mm)Setting descriptionStart voltage, end voltage, rise speed, arc detection,electrode distance, upper limit currentWaveform display contentVoltage, current, insulation resistanceSampling rate500 ext{ kS/s}Resolution256 ext{ words}Arc discharge detectionTest voltage variability: 1% to 50\%Contact check functionalityCapacitance measurement methodDetection methodCapacitance measurement methodSetting descriptionTest voltage variability: 1% to 50\%Contact check functionalitySave to USB memory$		1		
down time 1.1 s to 300 s / 0.1 s to 300 s, 01 Short-circuit current 200 mA or less Test modes W to IR, IR to W, program test Insulation resistance test 0.0 to 2000 V (1 V resolution) Output voltage DC 10 V to 2000 V (1 V resolution) Output setting accuracy ±(1.2% of setting + 2 V) Resistance value 10.00 kΩ to 200.0 GΩ (0.01 kΩ resolution) Accuracy guarantee range 10.00 kΩ to 99.99 GΩ Resistance accuracy ±(1.5% rdg. + 3 dgt.) *See below for details Test time 0.1 s to 300 s / 0.1 s to 300 s, off Breakdown voltage test 0.1 s to 300 s / 0.1 s to 300 s, off Settings Insulation breakdown voltage rise test, stepped voltage rise test Setting description Start voltage, end voltage, rise speed, arc detection, electrode distance, upper limit current Waveform display functionality Waveform display content Voltage, current, insulation resistance Sampling rate Solo kS/s Resolution Resolution 256 K words Arc discharge detection Test voltage variability: 1% to 50% Contact check functionality Capacitance measurement method Detection method Capacitance measurement metho		U.1 s to 999 s, continuous (timer off)		
Test modes W to IR, IR to W, program test Insulation resistance test Output voltage DC 10 V to 2000 V (1 V resolution) Output setting accuracy ±(1.2% of setting + 2 V) Resistance value display range 10.00 kΩ to 200.0 GΩ (0.01 kΩ resolution) Accuracy guarantee range 10.00 kΩ to 99.99 GΩ Resistance accuracy ±(1.5% rdg. + 3 dgt.)*See below for details Test time 0.1 s to 999 s, continuous (timer off) Voltage rise / fall time 0.1 s to 300 s / 0.1 s to 300 s, off Breakdown voltage test Test method Continuous voltage rise test, stepped voltage rise test Settings Insulation breakdown voltage (kV), insulation breakdown strength (kV/mm) Setting description Start voltage, end voltage, rise speed, arc detection, electrode distance, upper limit current Waveform display functionality Waveform display content Waveform display content Voltage, current, insulation resistance Sampling rate 500 kS/s Resolution 256 K words Arc discharge detection Detection method Detection method Monitoring of fluctuations in the test voltage Setting description Test voltage variability: 1% to 50% <	down time	·		
Insulation resistance test Output voltage DC 10 V to 2000 V (1 V resolution) Output setting accuracy display range ±(1.2% of setting + 2 V) Resistance value display range 10.00 kΩ to 200.0 GΩ (0.01 kΩ resolution) Accuracy guarantee range 10.00 kΩ to 299.99 GΩ Resistance accuracy ±(1.5% rdg. + 3 dgt.) *See below for details Test time 0.1 s to 999 s, continuous (timer off) Voltage rise / fall time 0.1 s to 300 s / 0.1 s to 300 s, off Breakdown voltage test Continuous voltage rise test, stepped voltage rise test Settings Insulation breakdown voltage (kV), insulation breakdown strength (kV/mm) Setting description Start voltage, end voltage, rise speed, arc detection, electrode distance, upper limit current Waveform display functionality Waveform display content Voltage, current, insulation resistance Sampling rate 500 kS/s Resolution 256 K words Arc discharge detection Detection method Monitoring of fluctuations in the test voltage Setting description Test voltage variability: 1% to 50% Contact check functionality Detection method Capacitance measurement method Setting description Test voltage variability: 1% to 50% Capacitanc				
Output voltage DC 10 V to 2000 V (1 V resolution) Output setting accuracy display range ±(1.2% of setting + 2 V) Resistance value display range 10.00 kΩ to 200.0 GΩ (0.01 kΩ resolution) Accuracy guarantee range 10.00 kΩ to 99.99 GΩ Resistance accuracy ±(1.5% rdg. + 3 dgt.) *See below for details Test time 0.1 s to 999 s, continuous (timer off) Voltage rise / fall time 0.1 s to 300 s / 0.1 s to 300 s, off Breakdown voltage test Test method Continuous voltage rise test, stepped voltage rise test Setting Insulation breakdown voltage (kV), insulation breakdown strength (kV/mm) Setting description Start voltage, end voltage, rise speed, arc detection, electrode distance, upper limit current Waveform display content Voltage, current, insulation resistance Sampling rate 500 kS/s Resolution 256 K words Arc discharge detection Test voltage variability: 1% to 50% Contact check functionality Detection method Detection method Capacitance measurement method Setting description Test voltage variability: 1% to 50% Contact check functionality Save to USB memory				
Output setting accuracy ±(1.2% of setting + 2 V) Resistance value 10.00 kΩ to 200.0 GΩ (0.01 kΩ resolution) Accuracy guarantee range 10.00 kΩ to 99.99 GΩ Resistance accuracy ±(1.5% rdg. + 3 dgt.) *See below for details Test time 0.1 s to 999 s, continuous (timer off) Voltage rise / fall time 0.1 s to 300 s / 0.1 s to 300 s, off Breakdown voltage test Test method Continuous voltage rise test, stepped voltage rise test Setting Insulation breakdown voltage (kV), insulation breakdown strength (kV/mm) Setting description Start voltage, end voltage, rise speed, arc detection, electrode distance, upper limit current Waveform display content Voltage, current, insulation resistance Sampling rate 500 kS/s Resolution 256 K words Arc discharge detection Detection method Monitoring of fluctuations in the test voltage Setting description Setting description Test voltage variability: 1% to 50% Contact check functionality Detection method Setting description Theshold (capacitance) setting: 1.0 nF to 100.0 nF Memory functionality Save to USB memory.	Insulation resistance tes			
Resistance value display range 10.00 kΩ to 200.0 GΩ (0.01 kΩ resolution) Accuracy guarantee range 10.00 kΩ to 290.99 GΩ Resistance accuracy ±(1.5% rdg. + 3 dgt.) *See below for details Test time 0.1 s to 999 s, continuous (timer off) Voltage rise / fall time 0.1 s to 300 s / 0.1 s to 300 s, off Breakdown voltage test Test method Continuous voltage rise test, stepped voltage rise test Settings Insulation breakdown voltage (kV), insulation breakdown strength (kV/mm) Setting description Start voltage, end voltage, rise speed, arc detection, electrode distance, upper limit current Waveform display functionality Waveform display content Voltage, current, insulation resistance Sampling rate Soo kS/s Resolution Resolution 256 K words Arc discharge detection Test voltage variability: 1% to 50% Contact check functionality Capacitance measurement method Setting description Test voltage measurement method Setting description Test voltage variability: 1% to 50% Contact check functionality Save to USB memory	•			
display range 10.00 kΩ to 200.0 GΩ (0.01 kΩ resolution) Accuracy guarantee range 10.00 kΩ to 99.99 GΩ Resistance accuracy ±(1.5% rdg. + 3 dgt.) *See below for details Test time 0.1 s to 399 s, continuous (timer off) Voltage rise / fall time 0.1 s to 300 s / 0.1 s to 300 s, off Breakdown voltage test Test method Continuous voltage rise test, stepped voltage rise test Settings Insulation breakdown voltage (kV), insulation breakdown strength (kV/mm) Setting description Start voltage, end voltage, rise speed, arc detection, electrode distance, upper limit current Waveform display functionality Waveform display content Voltage, current, insulation resistance Sampling rate Soo kS/s Setsing description Detection method Monitoring of fluctuations in the test voltage Setting description Test voltage variability: 1% to 50% Contact check functionality Detection method Detection method Capacitance measurement method Setting description Threshold (capacitance) setting: 1.0 nF to 100.0 nF Memory functionality Save to USB memory.		\pm (1.2% of setting + 2 V)		
Resistance accuracy ±(1.5% rdg. + 3 dgt.) *See below for details Test time 0.1 s to 999 s, continuous (timer off) Voltage rise / fall time 0.1 s to 300 s / 0.1 s to 300 s, off Breakdown voltage test Insulation breakdown voltage rise test, stepped voltage rise test Test method Continuous voltage rise test, stepped voltage rise test Settings Insulation breakdown voltage (kV), insulation breakdown strength (kV/mm) Setting description Start voltage, end voltage, rise speed, arc detection, electrode distance, upper limit current Waveform display functionality Waveform display content Voltage, current, insulation resistance Sampling rate 500 kS/s Setting description Detection method Monitoring of fluctuations in the test voltage Setting description Test voltage variability: 1% to 50% Contact check functionality Capacitance measurement method Detection method Capacitance) setting: 1.0 nF to 100.0 nF Memory functionality Save to USB memory.		10.00 k Ω to 200.0 G Ω (0.01 k Ω resolution)		
Test time 0.1 s to 999 s, continuous (timer off) Voltage rise / fall time 0.1 s to 300 s / 0.1 s to 300 s, off Breakdown voltage test Continuous voltage rise test, stepped voltage rise test Test method Continuous voltage rise test, stepped voltage rise test Settings Insulation breakdown voltage (kV), insulation breakdown strength (kV/mm) Setting description Start voltage, end voltage, rise speed, arc detection, electrode distance, upper limit current Waveform display functionality Waveform display content Voltage, current, insulation resistance Sampling rate 500 kS/s Start voltage variability: 1% to 50% Contact check functionality Detection method Contact check functionality Capacitance measurement method Setting description Test voltage variability: 1% to 50% Contact check functionality Save to USB memory Setting description Threshold (capacitance) setting: 1.0 nF to 100.0 nF	Accuracy guarantee range	10.00 kΩ to 99.99 GΩ		
Note of composition of the compositien of the composition of the composition	Resistance accuracy	\pm (1.5% rdg. + 3 dgt.) *See below for details		
Breakdown voltage test Test method Continuous voltage rise test, stepped voltage rise test Settings Insulation breakdown voltage (kV), insulation breakdown strength (kV/mm) Setting description Start voltage, end voltage, rise speed, arc detection, electrode distance, upper limit current Waveform display functionality Waveform display content Voltage, current, insulation resistance Sampling rate 500 kS/s Start voltage variability: 1% to 50% Contact check functionality Detection method Monitoring of fluctuations in the test voltage Setting description Test voltage variability: 1% to 50% Contact check functionality Detection method Capacitance measurement method Setting description Threshold (capacitance) setting: 1.0 nF to 100.0 nF Memory functionality Save to USB memory.	Test time	0.1 s to 999 s, continuous (timer off)		
Test method Continuous voltage rise test, stepped voltage rise test Settings Insulation breakdown voltage (kV), insulation breakdown strength (kV/mm) Setting description Start voltage, end voltage, rise speed, arc detection, electrode distance, upper limit current Waveform display functionality Waveform display content Waveform display content Voltage, current, insulation resistance Sampling rate 500 kS/s Resolution 256 K words Arc discharge detection Monitoring of fluctuations in the test voltage Setting description Test voltage variability: 1% to 50% Contact check functionality Capacitance measurement method Setting description Threshold (capacitance) setting: 1.0 nF to 100.0 nF Memory functionality Save to USB memory.		0.1 s to 300 s / 0.1 s to 300 s, off		
Settings Insulation breakdown voltage (kV), insulation breakdown strength (kV/mm) Setting description Start voltage, end voltage, rise speed, arc detection, electrode distance, upper limit current Waveform display functionality Waveform display content Waveform display content Voltage, current, insulation resistance Sampling rate 500 kS/s Resolution 256 K words Arc discharge detection Detection method Monitoring of fluctuations in the test voltage Setting description Test voltage variability: 1% to 50% Contact check functionality Detection method Capacitance measurement method Setting description Threshold (capacitance) setting: 1.0 nF to 100.0 nF Memory functionality Save to USB memory.	ě			
Settings strength (kV/mm) Setting description Start voltage, end voltage, rise speed, arc detection, electrode distance, upper limit current Waveform display functionality Waveform display content Waveform display content Voltage, current, insulation resistance Sampling rate 500 kS/s Resolution 256 K words Arc discharge detection Monitoring of fluctuations in the test voltage Setting description Test voltage variability: 1% to 50% Contact check functionality Capacitance measurement method Setting description Threshold (capacitance) setting: 1.0 nF to 100.0 nF Memory functionality Save to USB memory.	Test method			
Setting description electrode distance, upper limit current Waveform display functionality Waveform display content Waveform display content Voltage, current, insulation resistance Sampling rate 500 kS/s Resolution 256 K words Arc discharge detection Detection method Detection method Monitoring of fluctuations in the test voltage Setting description Test voltage variability: 1% to 50% Contact check functionality Detection method Setting description Threshold (capacitance) setting: 1.0 nF to 100.0 nF Memory functionality Save to USB memory.	Settings			
Waveform display content Voltage, current, insulation resistance Sampling rate 500 kS/s Resolution 256 K words Arc discharge detection Detection method Detection method Monitoring of fluctuations in the test voltage Setting description Test voltage variability: 1% to 50% Contact check functionality Detection method Setting description Threshold (capacitance) setting: 1.0 nF to 100.0 nF Memory functionality Save to USB memory.	Setting description			
Sampling rate 500 kS/s Resolution 256 K words Arc discharge detection Detection method Detection method Monitoring of fluctuations in the test voltage Setting description Test voltage variability: 1% to 50% Contact check functionality Detection method Capacitance measurement method Setting description Setting description Threshold (capacitance) setting: 1.0 nF to 100.0 nF Memory functionality Saving of waveforms/ Saving of waveforms/ Save to USB memory	Waveform display functi	onality		
Resolution 256 K words Arc discharge detection Detection method Detection method Monitoring of fluctuations in the test voltage Setting description Test voltage variability: 1% to 50% Contact check functionality Detection method Capacitance measurement method Setting description Setting description Threshold (capacitance) setting: 1.0 nF to 100.0 nF Memory functionality Saving of waveforms/ Saving of waveforms/ Save to USB memory.	Waveform display content	Voltage, current, insulation resistance		
Arc discharge detection Monitoring of fluctuations in the test voltage Detection method Monitoring of fluctuations in the test voltage Setting description Test voltage variability: 1% to 50% Contact check functionality Detection method Capacitance measurement method Setting description Threshold (capacitance) setting: 1.0 nF to 100.0 nF Memory functionality Saving of waveforms/ Save to USB memory.	Sampling rate	500 kS/s		
Detection method Monitoring of fluctuations in the test voltage Setting description Test voltage variability: 1% to 50% Contact check functionality Detection method Capacitance measurement method Capacitance) setting: 1.0 nF to 100.0 nF Memory functionality Saving of waveforms/ Saving of waveforms/ Save to USB memory	Resolution	256 K words		
Setting description Test voltage variability: 1% to 50% Contact check functionality Detection method Capacitance measurement method Setting description Threshold (capacitance) setting: 1.0 nF to 100.0 nF Memory functionality Saving of waveforms/ Save to USB memory	Arc discharge detection			
Contact check functionality Detection method Capacitance measurement method Setting description Threshold (capacitance) setting: 1.0 nF to 100.0 nF Memory functionality Saving of waveforms/ Saving of waveforms/ Save to USB memory	Detection method	Monitoring of fluctuations in the test voltage		
Detection method Capacitance measurement method Setting description Threshold (capacitance) setting: 1.0 nF to 100.0 nF Memory functionality Saving of waveforms/ Saving of waveforms/ Save to USB memory		<u> </u>		
Setting description Threshold (capacitance) setting: 1.0 nF to 100.0 nF Memory functionality Saving of waveforms/ Save to USB memory				
Memory functionality Saving of waveforms/ Save to USB memory				
Saving of waveforms/ Save to USB memory		moonora (oapaoitanoo) sotiing. 1.0 m to 100.0 m		
		Save to USB memory Save formats: BMP, PNG, CSV		

	Saves test condition settings internally in the instrument.
Development for the	DC withstand voltage testing/insulation resistance testing: Up to 64 sets of settings each
Panel memory function	Program testing: Up to 30 programs (max. 50 steps)
	Insulation breakdown voltage testing: Up to 10 sets of settings
Data momony function	Saves measured values in the instrument's internal memo-
Data memory function	ry (up to 32,000 values).
Judgment functionality	
	PASS judgment, FAIL judgment (UPPER FAIL, LOWER FAIL)
Judgment output	UPPER_FAIL: Measured value > upper limit value PASS : Upper limit value \geq measured value \geq lower limit value
	LOWER FAIL : Measured value < lower limit value
List of major functions	
Interlock	Disables output based on the status of an external device.
GFI	Protects workers from electric shock.
-	Discharges the target via internal circuitry at the end of
Auto discharge	the test. Discharge resistance: 700 kΩ
Offset cancellation	Measures the current flowing along the test path and subtracts it from measurement results.
Set voltage modification during testing	Allows the set voltage to be changed during testing using either the rotary knob or communications commands.
Momentary out	Outputs the test voltage only while the START button is being pressed.
Command monitor	Displays commands being sent and received on the screen.
I/O handler test	Allows you to check whether signals are being input and output properly via the EXT I/O terminal.
Key lock	Disables changes to test conditions.
Self-check	Checks the touch screen, display, LED, instrument memory, and EXT I/O.
Calibration deadline check	Lets you set a calibration deadline in advance and dis- plays a warning once it's passed.
	Allows the instrument to be operated using a remote control.
EXT SW	Options: Remote control box (single) 9613, Remote control box (dual) 9614
Basic specifications	
Operating temperature and humidity range	0°C to 40°C, 80% RH or less (non-condensing)
Standard compliance	Safety: IEC 61010
•	EMC: IEC 61326
Power supply	100 to 240 V AC
Power consumption	Approx. 180 VA*
Maximum rated power	800 VA
Interface	Communications: USB, LAN, EXT I/O
Internace	Options: RS-232C (Z3001), GP-IB (Z3000) Memory: USB drive
External dimensions	305 mm (12.01 in) W \times 142 mm (5.59 in) H \times 430 mm (16.93 in) D (excluding parts)
Weight	10.0 kg (352.74 oz) ±0.2 kg (7.05 oz)
Product warranty	3 years
Accessories	Power cord, CD-ROM (PDF: User Manual, Communica- tions Manual), EXT I/O male connector, EXT I/O connector cover, EXT I/O interlock cancellation jig, Startup Guide

*Power supply conditions are 220 V power supply voltage, 50/60 Hz power supply frequency, DC withstand voltage test mode, 2.5 kV test voltage, and 5 mA load current (500 kΩ load resistance).

Insulation resistance measurement accuracy (Accuracy guaranteed test voltage range: 50 V to 2000 V)

	Mea	asurement range	10 kΩ to 99.99 GΩ ^{*1}		
		10 00 < 1 < 2 10	100 MΩ to 999.9 MΩ	±(20% rdg.)	
		10 nA ≤ l ≤ 3 µA	1.00 GΩ to 99.99 GΩ	*2, *3, *4	
	100 - 0	10.00 MΩ to 99.99 MΩ	±(5% rdg.)		
		100 nA ≤ I ≤ 30 µA	100.0 MΩ to 999.9 MΩ	*2, *3, *4	
IR Accuracy	1 μA ≤ I ≤ 300 μA	1.000 MΩ to 9.999 MΩ	±(2% rdg. + 5 dgt.)		
		10.00 MΩ to 99.99 MΩ	*2, *3, *4		
	10	100.0 kΩ to 999.9 kΩ			
	$10 \ \mu A \le I \le 3 \ mA$	1.000 MΩ to 9.999 MΩ			
	100	10.00 kΩ to 99.99 kΩ	±(1.5% rdg. + 3 dgt.)		
		100 µA ≤ I ≤ 30 mA	100.0 kΩ to 999.9 kΩ	2, 0, 11	
		$1 \text{ mA} \le I \le 100 \text{ mA}$	10.00 kΩ to 99.99 kΩ		

*1: For maximum rating 500 VA range *2: If the test voltage is 10 V to 99 V, add ±10% to the measurement accuracy. *3: If the test voltage is 100 V to 999 V, add ±5% to the measurement accuracy. *4: If the test voltage is 1000 V to 2000 V, add ±2% to the measurement accuracy.



DISTRIBUTED BY

HIOKI E.E. CORPORATION

HEADQUARTERS

81 Koizumi, Ueda, Nagano 386-1192 Japan https://www.hioki.com/



Scan for all regional contact information

Product name

Note: Company names and product names appearing in this brochure are trademarks or registered trademarks of various companies.

DC HIPOT TESTER ST5680

Model number (order code) : ST5680



The instrument is not able to perform measurement by itself. The HIGH and LOW terminals use dedicated Hioki connectors to which only Hioki options L2260 and L2261 can be connected. Please purchase optional test leads as appropriate for your measurement application.